

DPI Protected Verilog Instead of Encryption

A non-broken and open source friendly alternative to IEEE 1735

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IP is everywhere

- Modular hardware components
- Licensed by a third party
- Term clearly coined by lawyers
- IEEE P1735 standardizes RTL encryption

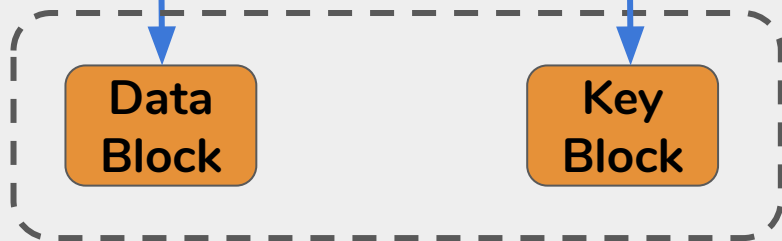
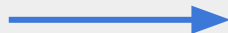


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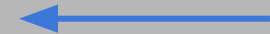
IP Vendor

RTL



Data Block

Key Block



RTL

EDA Process

Open source tools can't play



Possible solutions:

Use closed source simulator 

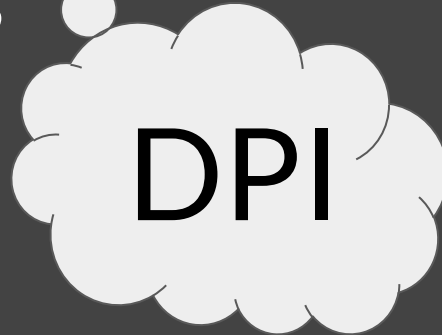
Emulate functionality 

Gate-level sim 

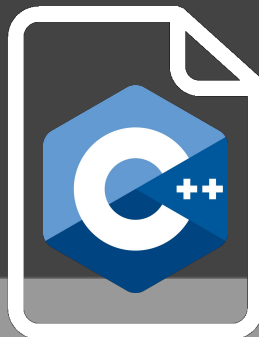
Negotiate for source 

Give up 

What if we could
compile the secret
Verilog and use it via
a standardized
interface?



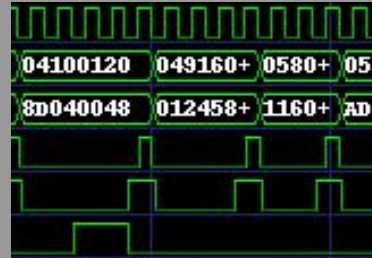
Building the library



Using the library



VERILATOR



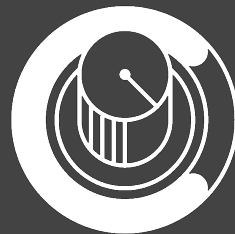
Let's add it all up

- Portable across DPI-capable simulators
- Including open source simulators
- Compiled library is pretty indecipherable
- No possibility of leaked RTL
- Stable API via the DPI
- Could lead to fewer trusted keys

Is everything fine?

- Everything is not fine





Top-level parameters

- Verilator requires fixed top-level parameters
- Possible solutions:
 - Don't do that
 - Build libraries on-demand
 - Convert parameters to wires?
 - Dynamically construct hierarchy?



Build matrix

- OS
- Machine architecture
- C++ ABI
- Static or shared library

Try it out

```
$ git clone -b protect-lib  
https://github.com/toddstrader/verilator-dev.git  
  
$ # build Verilator  
  
$ make -C examples/dpi_protect_lib/  
  
$ test_regress/t/t_prot_lib.pl  
  
$ test_regress/t/t_prot_lib.pl --xsim
```

Next steps

- Land upstream
- Larger tests
 - verilator_ext_tests
 - Benchmarking
- Test more commercial simulators
- Support x's and z's
- Isolate Verilator runtime
- Performance optimizations
- Better obfuscation
- VCD replay
- Support top-level parameters

// Thanks

```
$ verilator --cc --protect-lib secret
```

Further reading

- <https://acmccs.github.io/papers/p1533-chhotarayA.pdf>
- <https://thehackernews.com/2017/11/ieee-p1735-ip-encryption.html>
- <https://standards.ieee.org/content/ieee-standards/en/standard/1735-2014.html>